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# Non-destructive testing — Equipment for eddy current examination —

## Part 2: Probe characteristics and verification

*Essais non destructifs — Appareillage pour examen par courants  
de Foucault —*

*Partie 2: Caractéristiques des capteurs et vérifications*



Reference number  
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## Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2. [www.iso.org/directives](http://www.iso.org/directives)

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Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

The committee responsible for this document is ISO/TC 135, *Non-destructive Testing*, Subcommittee SC 4, *Eddy current methods*.

This second edition cancels and replaces the first edition (ISO 15548-2:2008), of which it constitutes a minor revision.

ISO 15548 consists of the following parts, under the general title *Non-destructive testing — Equipment for eddy current examination*:

- *Part 1: Instrument characteristics and verification*
- *Part 2: Probe characteristics and verification*
- *Part 3: System characteristics and verification*